

Specification of Automotive MLCC (Reference sheet)

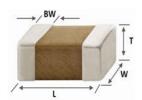


● Supplier : Samsung Electro-Mechanics ● Samsung P/N : CL21B105KOFVPNE

● AEC-Q200 Qualified

A. Dimension

Dimension



Size	0805 inch				
L	2.00±0.10 mm				
W	1.25±0.10 mm				
Т	1.25±0.10 mm				
BW	0.50+0.20/-0.30 mm				

B. Samsung Part Number

<u>CL</u>	<u>21</u>	<u>B</u>	<u>105</u>	<u>K</u>	<u>o</u>	<u>F</u>	<u>v</u>	<u>P</u>	<u>N</u>	<u>E</u>
1	2	3	4	5	⑥	1	8	9	10	11

① Series	Samsung Multi-layer Ceramic Capacitor		
② Size	0805 (inch code)	L: 2.00±0.10 mm	W :1.25±0.10 mm
③ Dielectric	X7R	® Inner electrode	Ni
Capacitance	1 <i>μ</i> F	Termination	Metal-Epoxy
⑤ Capacitance	± 10%	Plating	Sn 100% (Pb Free)
tolerance		9 Product	Automotive
Rated Voltage	16 V	Special code	Normal
7 Thickness	1.25±0.10 mm	1 Packaging	Embossed Type, 7" Reel

C. Reliability Test and Judgement condition

Test items	Performance	Test condition
High Temperature	Appearance : No abnormal exterior appearance	Unpowered, 1,000hrs @ Max. temperature
Exposure	Capacitance Change Within ±10 %	Measurement at 24±2hrs after test conclusion
	Tan δ :0.05 max.	
	IR :More than 10,000 MΩ or 500 MΩ×μF	Initial Measurement 2*
	Whichever is smaller	Final Measurement 3*
Temperature Cycling	Appearance : No abnormal exterior appearance	1,000Cycles
	Capacitance Change Within ±10 %	Initial Measurement 2*
	Tan δ :0.05 max.	Final Measurement 3*
	IR : More than 10,000 № or 500 №×μF	Measurement at 24±2hrs after test conclusion
	Whichever is smaller	1 cycle condition : $-55+0/-3$ °C (30±3min) \rightarrow Room Temp. (1min)
		→ 125+3/-0 °C (30±3min) → Room Temp. (1min)
Destructive Physical	No Defects or abnormalities	Per EIA 469
Analysis		
Humidity Bias	Appearance : No abnormal exterior appearance	1,000hrs 85℃/85%RH, Rated Voltage and 1.3~1.5V,
	Capacitance Change Within ±12.5 %	Add 100kohm resistor
	Tan δ :0.05 max.	Initial Measurement 2*
	IR :More than 500 № or 25 №× <i>µ</i> F	Final Measurement 4*
	Whichever is smaller	Measurement at 24±2hrs after test conclusion
		The charge/discharge current is less than 50mA.
High Temperature	Appearance : No abnormal exterior appearance	1,000hrs @ 125℃, 200% Rated Voltage,
Operating Life	Capacitance Change Within ±12.5 %	Initial Measurement 2*
	Tan δ :0.05 max.	Final Measurement 4*
	IR :More than 1,000 № or 50 №× μF	Measurement at 24±2hrs after test conclusion
	Whichever is smaller	The charge/discharge current is less than 50mA.
		The state of the s

	Performance	Test condition					
External Visual	No abnormal exterior appearance	Microscope ('10)					
Physical Dimension	Within the specified dimensions	Using The calipers					
Mechanical Shock	Appearance : No abnormal exterior appearance	Three shocks in each direction should be applied along					
	Capacitance Change Within ±10 %	3 mutually perpendicular axes of the test specimen (18 shocks)					
	Tan δ, IR : Initial spec.	Peak value Duration Wave Velocity					
			1,500G	0.5ms	Half sine	4.7m/sec	
		Initial Measurement 2*					
		Final Measurement 5*					
Vibration	Appearance : No abnormal exterior appearance	5g's for 20min., 12cycles each of 3 orientations,					
	Capacitance Change Within ±10 %	Use 8	"×5" PCB 0	.031" Thick	7 secure p	oints on one lo	ong side
	Tan δ, IR : Initial spec.	and 2	secure poir	nts at corne	rs of oppos	site sides. Part	s mounted
		within	2" from any	secure po	int. Test fro	om 10~2,000Hz	
		Initial	Measureme	ent 2*			
		Final Measurement 5*					
Resistance to	Appearance : No abnormal exterior appearance	prehea	ating : 150°	C for 60~12	20 sec.		
Solder Heat	Capacitance Change Within ±10 %	preheating : 150°C for 60~120 sec. Solder pot : 260±5°C, 10±1sec.					
	Tan δ, IR : Initial spec.	Initial Measurement 2*					
		Final Measurement 3*					
ESD	Appearance : No abnormal exterior appearance	AEC-Q200-002 or ISO/DIS10605					
	Capacitance Change Within ±10 %	Initial Measurement 2*					
	Tan δ, IR : Initial spec.	Final Measurement 4*					
Solderability	95% of the terminations is to be soldered	a) Preheat at 155°C for 4 hours, Immerse in solder for 5s at 245±5°C					
	evenly and continuously	b) Steam aging for 8 hours, Immerse in solder for 5s at 245±5 $^{\circ}\!\mathrm{C}$					
		c) Steam aging for 8 hours, Immerse in solder for 120s at 260±5°C					
		solder : a solution ethanol and rosin					
Electrical	Capacitance : Within specified tolerance	*A capacitor prior to measuring the capacitance is heat treated at					it treated at
Characterization	Tan δ : 0.035 max.	150 +0/-10°C for 1hour and maintained in ambient air for 24±2 ho					for 24±2 hours
	IR(25℃): More than 10,000 № or 500 №× <i>µ</i> F	The Capacitance / D.F. should be measured at 25 ℃,					
	Whichever is smaller	1 灺 ± 10%, 1 ± 0.2 Vrms					
	IR(125℃) More than 1,000 № or 10 № × μF	I.R. should be measured with a DC voltage not exceeding					ding
	Whichever is smaller	Rated	Voltage @	25℃, @ 12	5℃ for 60	~120 sec.	
	Dielectric Strength	Dielectric Strength : 250% of the rated voltage for 1~5 seconds					seconds
Board Flex	Appearance : No abnormal exterior appearance	Bendi	ng to the lin	nit, 3 mm fo	r 60 secon	ds 1*	
	Capacitance Change Within ±10 %	Initial	Measureme	ent 2*			
		Final I	Measureme	nt 5*			
Terminal	Appearance : No abnormal exterior appearance	18 N,	for 60 sec.				
Strength(SMD)	Capacitance Change Within ±10 %	Initial	Measureme	ent 2*			
		Final Measurement 5*					
Beam Load	Destruction value should be exceed 20 N	20 N Beam speed: 0.5±0.05 mm/sec					
Temperature	X7R						
Characteristics	From -55 ℃ to 125 ℃, Capacitance change shou	d be wi	ithin ±15%				

D. Recommended Soldering method :

Reflow (Reflow Peak Temperature : 260 +0/-5°C, 30sec.), Meet IPC/JEDEC J-STD-020 D Standard

- *1 : The figure indicates typical specification. Please refer to individual specifications.
- *2 : Initial measurement : Perform a heat treatment at 150 +0/-10 $^{\circ}\mathrm{C}$ for one hour after soldering process. and then let sit for 24±2 hours at room temperature. Perform the initial measurement.
- $^{\star}3$: Final measurement : Let sit for 24 \pm 2 hours at room temperature after test conclusion, then measure.
- *4 : Final measurement : Perform a heat treatment at 150 +0/-10 °C for one hour after soldering process. and then let sit for 24±2 hours at room temperature. Perform the initial measurement.
- *5 : Final measurement : Let measure within 24 hours at room temperature after test conclusion.



Product specifications included in the specifications are effective as of March 1, 2013.

Please be advised that they are standard product specifications for reference only.

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- ② Medical equipment
- 3 Military equipment
- 4 Disaster prevention/crime prevention equipment
- ⑤ Power plant control equipment
- 6 Atomic energy-related equipment
- ① Undersea equipment
- 8 Traffic signal equipment
- Data-processing equipment
- @ Electric heating apparatus, burning equipment
- Safety equipment
- @ Any other applications with the same as or similar complexity or reliability to the applications